

FORM PTO-1449		DOCKET NUMBER SMT 391		APPLICATION NUMBER	
INFORMATION DISCLOSURE CITATION IN AN APPLICATION		APPLICANT Meral Bradley Woodberry			
		FILING DATE: March 15, 2000		GROUP ART UNIT	
U. S. PATENT DOCUMENTS					
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	5,047,711	09/10/91	Smith et al.	324	158R
	4,968,931	11/06/90	Littlebury et al.	324	158R
FOREIGN PATENT DOCUMENTS					
	DOCUMENT NUMBER	DATE	COUNTRY/NAME	CLASS	SUB CLASS
OTHER DOCUMENTS					
	Article entitled, "Securing Known Good Die", by T. A. Williams, published in Advanced Packaging, Fall 1992, pp. 50-59				
	Article entitled, "Known-Good Die Poised to Take Off", by D. Maliniak, published in Electronic Design, 11-21-94, pp. 55-73				
	Article entitled, "Burn-In Co-Developed by TI, MicroModule System, Intel Launches 'SmartDie' Program, by Jim Detar, published in Electronic News, May 30, 1994				
	Article entitled, "Known Good Die: A Commercial Solution for Burn-in and Test Before Packaging" by S-H Foo and L. Prokopchak, presented at Semicon Japan, 12-94				
	Article entitled, "Flexibility and Modularity Drive Today's Burn-In/Test Systems" by P. Mayerfeld, reprinted from EE-Evaluation Engineering, November 1994				
	Specification entitled, "Known Good Die - The Total Solution", AEHR Test Systems/Nitto-Denko				
EXAMINER			DATE CONSIDERED		

U.S. PTO
09/526955
03/16/00